## April 2005

## SEMICONDUCTOR®

## **FDG327NZ** 20V N-Channel PowerTrench<sup>o</sup> MOSFET

## **General Description**

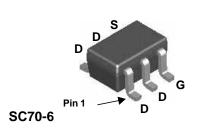
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized use in small switching regulators, providing an extremely low  $R_{\text{DS(ON)}}$  and gate charge  $(\text{Q}_{\text{G}})$  in a small package.

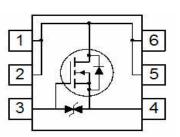
## Applications

- DC/DC converter
- Power management
- Load switch

## Features

- Fast switching speed
- Low gate charge
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability.





## Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DSS</sub>	Drain-Source Voltage			20	V	
V <sub>GSS</sub>	Gate-Source Voltage			± 8		
ID	Drain Current – Continuous (Note 1a)		(Note 1a)	1.5	A	
		- Pulsed		6		
P <sub>D</sub>	Power Diss	ipation for Single Operation	(Note 1a)	0.42	W	
			(Note 1b)	0.38		
T <sub>J</sub> , T <sub>STG</sub>	Operating a	ting and Storage Junction Temperature Range		-55 to +150		
	l Charac			222		
R <sub>θJA</sub>	1	teristics sistance, Junction-to-Ambie	nt (Note 1a)	300	°C/W	
$R_{ ext{ hetaJA}}$	Thermal Re		· · ·	300 333	°C/W	
R <sub>0JA</sub> R <sub>0JA</sub> Packag	Thermal Re Thermal Re <b>e Markin</b>	esistance, Junction-to-Ambie esistance, Junction-to-Ambie g and Ordering In	nt (Note 1b)		°C/W	
R <sub>eja</sub> R <sub>eja</sub> Packag	Thermal Re Thermal Re	esistance, Junction-to-Ambie esistance, Junction-to-Ambie g and Ordering In	nt (Note 1b)		°C/W	

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FDG327NZ

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 V$ , $I_{D} = 250 \mu A$	20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to $25^{\circ}$ C		11		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 16 \text{ V}, \qquad V_{\text{GS}} = 0 \text{ V}$			1	μA
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS}=\pm 8~V, \qquad V_{DS}=0~V$			±10	μΑ
On Chara	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	0.4	0.7	1.5	V
$\Delta V_{GS(th)}$ $\Delta T_{J}$	Gate Threshold Voltage Temperature Coefficient	ID = 250 $\mu$ A, Referenced to 25°C		-2		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$ \begin{array}{l} V_{GS} = 4.5 \ V, & I_D = 1.5 \ A \\ V_{GS} = 2.5 \ V, & I_D = 1.4 \ A \\ V_{GS} = 1.8 \ V, & I_D = 1.2 \ A \\ V_{GS} = 4.5 \ V, & I_D = 1.5 \ A, \ T_J = 125^\circ C \end{array} $		68 77 90 86	90 100 140 123	mΩ
I <sub>D(on)</sub>	On–State Drain Current	$V_{GS} = 4.5V,  V_{DS} = 5V$	3			Α
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 1.5 \text{ A}$		2.2		S
Dvnamic	Characteristics		1			•
Ciss	Input Capacitance	$V_{DS} = 10 \text{ V},  V_{GS} = 0 \text{ V}$		412		pF
Coss	Output Capacitance	f = 1.0 MHz		81		pF
Crss	Reverse Transfer Capacitance	1		44		pF
R <sub>G</sub>	Gate Resistance	$V_{GS} = 15 \text{ mV}, \text{ f} = 1.0 \text{ MHz}$		1.9		Ω
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn–On Delay Time	$V_{DD} = 10 V, I_D = 1 A,$		13	23	ns
tr	Turn–On Rise Time	$V_{GS} = 4.5 \text{ V},  R_{GEN} = 6 \Omega$		12	22	ns
t <sub>d(off)</sub>	Turn–Off Delay Time	1		33	53	ns
t <sub>f</sub>	Turn–Off Fall Time	1		18	20	ns
Qg	Total Gate Charge	$V_{DS} = 10 \text{ V}, \qquad I_D = 1.5 \text{ A},$		4.2	6	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 4.5 V$		0.4		nC
Q <sub>gd</sub>	Gate-Drain Charge			1		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings				
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 0.32 \text{ A}  (\text{Note 2})$		0.6	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = 1.5 \text{ A},  d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		4		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	1		2		nC



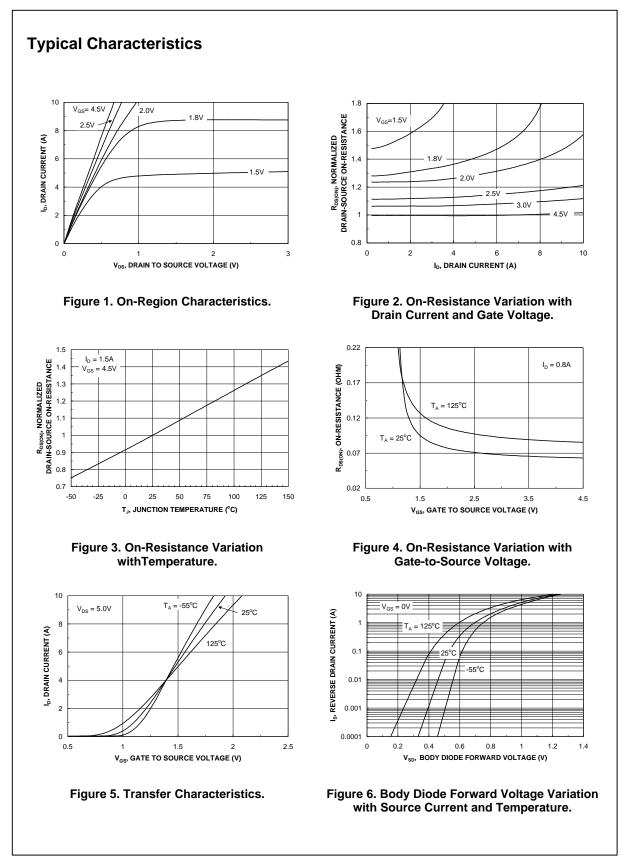
a) 300°C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper.



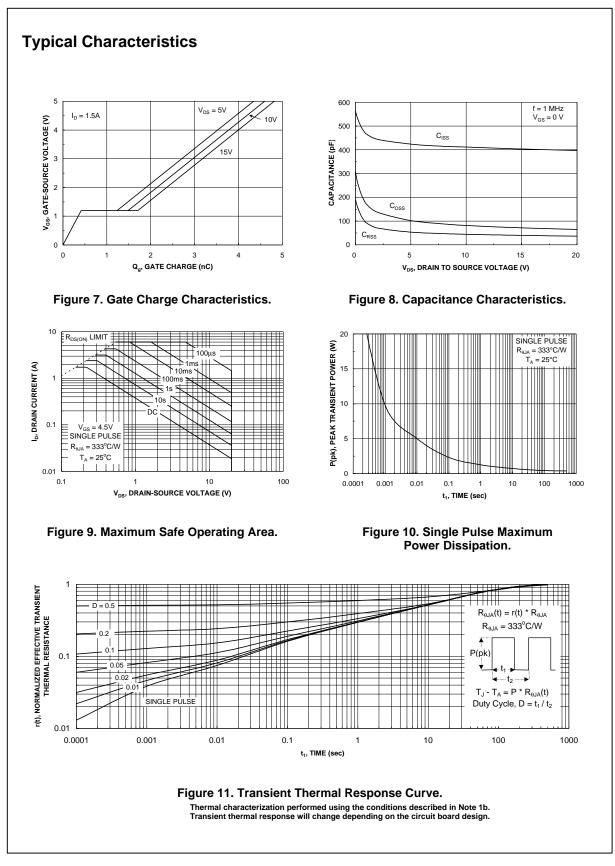
b) 333°C/W when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width < 300 $\mu$ s, Duty Cycle < 2.0%

FDG327NZ Rev C(W)



# FDG327NZ



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